

## CBCS SCHEME

15EC63

## Sixth Semester B.E. Degree Examination, Jan./Feb. 2021 **VLSI Design**

Time: 3 hrs.

Max. Marks: 80

Note: Answer any FIVE full questions, choosing ONE full question from each module.

## Module-1

- Explain the nmos enhancement mode transistor operation for different values of V<sub>GS</sub> 1 and V<sub>DS</sub>.
  - Obtain the transfer characteristics of a CMOS inverter mark all the region, showing the status of PMOS and nmos transistor. (10 Marks)

OR

- Explain the fabrication steps of CMOS P-well process with neat diagram, and write all the mask sequence. (10 Marks)
  - Distinguish between CMOS and bipolar technologies

(06 Marks)

With neat diagram, describe the design rules i) Transistor ii) wires (iii) contact cut.

(08 Marks)

Draw the Schematic and Mask Layout for the expression  $Y = \overline{AB + CD}$ . (08 Marks)

OR

Derive the expression for the Rise time and fall time for CMOS inverter.

Two MOS inverters are cascaded to drive a capacitive load C<sub>L</sub> = 14cg as shown in Fig Q4(b). Calculate the pair delays  $V_{in}$  to  $V_{out}$  in terms of  $\tau$ .



Fig Q4(b)

(06 Marks)

## Module-3

Why do we require scaling of MOS circuits?

(04 Marks)

- Find the scaling factors for the following:
  - i) Gate capacitance (C<sub>g</sub>)
- ii) Saturation current (I<sub>ds</sub>)
- iii) Gate capacitance per unit area (C<sub>ox</sub>)
- iv) Carrier density in channel (Q<sub>ON</sub>)
- v) Maximum frequency of operation (f<sub>0</sub>) vi) Speed power product (P<sub>T</sub>)
- (12 Marks)

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6	a. b.	OR Discuss the General considerations of the subsystem Design process. Explain a standard Adder element using nmos version of adder logic.	(06 Marks) (10 Marks)
7	a. b.	Module-4 Explain the multiplexer/Data selections with layout. Explain parity Generator with stick diagram.	(10 Marks) (06 Marks)
8	a. b.	OR Briefly explain Architecture of FPGA. Explain Antifuse base FPGA.	(10 Marks) (06 Marks)
9	a. b.	Explain one transistor DRAM. Explain Three Transistors DRAM.	(08 Marks) (08 Marks)
10	a. b.	OR  Explain objectives of Functional Testing.  Define fault model, explain the  i) Stuck – at Faults  ii) Stuck – open and stuck – short Fault	(06 Marks)
		iii) Stuck – open Fault  *****	(10 Marks)
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